

Masanobu Yoshikawa

List of Publications by Year in descending order

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Version: 2024-02-01

6
papers

42
citations

1937685

4
h-index

2053705

5
g-index

6
all docs

6
docs citations

6
times ranked

31
citing authors

#	ARTICLE	IF	CITATIONS
1	Stress Characterization of 4H-SiC Metal-Oxide Semiconductor Field-Effect Transistor (MOSFET) using Raman Spectroscopy and the Finite Element Method. Applied Spectroscopy, 2016, 70, 1209-1213.	2.2	13
2	Abnormal Behavior of Longitudinal Optical Phonon in Silicon Dioxide Films on 4H-SiC Bulk Epitaxial Substrate Using Fourier Transform Infrared (FT-IR) Spectroscopy. Applied Spectroscopy, 2013, 67, 542-545.	2.2	10
3	Stress Characterization of Si by Near-Field Raman Microscope Using Resonant Scattering. Applied Spectroscopy, 2006, 60, 479-482.	2.2	7
4	Characterization of Thermal Oxides on 4H-SiC Epitaxial Substrates Using Fourier-Transform Infrared Spectroscopy. Applied Spectroscopy, 2017, 71, 911-918.	2.2	6
5	Stress Characterization of the Interface Between Thermal Oxide and the 4H-SiC Epitaxial Layer Using Near-Field Optical Raman Microscopy. Applied Spectroscopy, 2019, 73, 1193-1200.	2.2	4
6	Characterization of Inhomogeneity in Thermal Oxide SiO_2 Films on 4H-SiC Epitaxial Substrates by a Combination of Fourier Transform Infrared Spectroscopy and Cathodoluminescence Spectroscopy. Materials Science Forum, 0, 924, 273-276.	0.3	2